Apacer

RoHS Compliant

PCI Express Flash Drive

Industrial PT160-M280 BiCS5 Product Specifications

July 4, 2024

Version 1.2

Specifications Overview:

- **PCIe Interface**
  - Compliant with PCI Express 4.0
  - Compliant with NVMe 1.4
  - Compatible with PCIe Gen4 x4 interface

- **Capacity**
  - 4, 8 TB

- **Performance[1]**
  - Interface burst read/write: 8 GB/sec
  - Sequential read: up to 6,970 MB/sec
  - Sequential write: up to 2,310 MB/sec
  - Random read (4K): up to 909,000 IOPS
  - Random write (4K): up to 517,000 IOPS

- **DRAM Cache for Enhanced Random Performance**

- **Flash Management**
  - Low-Density Parity-Check (LDPC) Code
  - Global Wear Leveling
  - Flash bad-block management
  - Flash Translation Layer: Page Mapping
  - Power Failure Management
  - S.M.A.R.T.
  - TRIM
  - SMART Read Refresh™
  - NVMe Secure Erase

- **NAND Flash Type:** 3D TLC (BiCS5)

- **MTBF:** >3,000,000 hours

- **Endurance (in drive writes per day: DWPD)**
  - 4 TB: 2.30 DWPD
  - 8 TB: 1.54 DWPD

- **Temperature Range**
  - Operating (Tc):
    - Standard: 0°C to 70°C
    - Wide[2]: -40°C to 85°C
  - Storage (Ta): -55°C to 100°C

- **Supply Voltage**
  - 3.3V ± 5%

- **Power Consumption[1]**
  - Active mode (Max.): 3,750 mA
  - Idle mode: 900 mA

- **Power Management**
  - Supports APST
  - Supports ASPM L1.2

- **Security**
  - AES 256-bit hardware encryption

- **Reliability**
  - Thermal Sensor
  - Thermal Throttling
  - Sidefill
  - End-to-End Data Protection
  - Heat Spreader

- **Connector Type**
  - 75-pin M.2 module pinout

- **Physical Characteristics**
  - Form factor: Double-sided M.2 2280-M
  - Dimensions: 22.00 x 80.00 x 4.08$_{(max.)}$, unit: mm
  - Net weight: 11.9g ± 5%

- **LED Indicators for Drive Behavior**

- **RoHS Compliant**

Notes:
1. Varies from capacities. The values for performances and power consumptions presented are typical and may vary depending on flash configurations or platform settings.
2. Not supported on 8TB

Table of Contents

1. General Description

Apacer PT160-M280 is the fastest SSD designed with M.2 2280 mechanical dimensions, providing full compliance with PCIe Gen4 x4 interface and NVMe 1.4 specifications. This enables it to operate in power management modes and significantly reduce power consumption. Equipped with a powerful PCIe controller supporting on-the-module ECC and an efficient wear leveling scheme, PT160-M280 delivers exceptionally low latency and outstanding performance in data transfer. With its compact size and high-speed storage, PT160-M280 is the ideal choice for larger, faster hosts deployed across a wide range of applications that demand exceptional performance.

Utilizing 3D NAND technology for capacities up to 8TB and delivering superior power efficiency compared to 2D NAND, PT160-M280 goes beyond mere storage. It integrates an LDPC (Low Density Parity Check) ECC engine to enhance SSD endurance and data reliability. Additionally, it features a built-in thermal sensor that monitors SSD temperature through S.M.A.R.T commands, coupled with thermal throttling to dynamically adjust frequency scaling, ensuring sustained performance while preventing overheating.

To ensure reliable operation in harsh conditions, Apacer has integrated Sidefill technology, enhancing product durability and resistance to various thermal and mechanical stresses. Furthermore, the inclusion of a graphene heat spreader aids in maintaining optimal operating temperatures, ensuring the SSD remains cool and functions correctly. For demanding applications, PT160-M280 also features End-to-End Data Protection, which safeguards data integrity at multiple points along the data transfer path, enabling dependable delivery of data transfers.

In terms of security, Advanced Encryption Standard (AES) safeguards data, giving users peace of mind that their information is protected against unauthorized access. PT160-M280 also includes advanced features, including flash block management, power failure management, TRIM, page mapping, SMART Read Refresh, NVMe secure erase, and power saving modes.

With exceptional performance, reliable dependability, and enhanced data protection, PT160-M280 is the ideal storage or cache solution for a variety of applications, including industrial, imaging, computing, and enterprise markets.

2. Functional Block
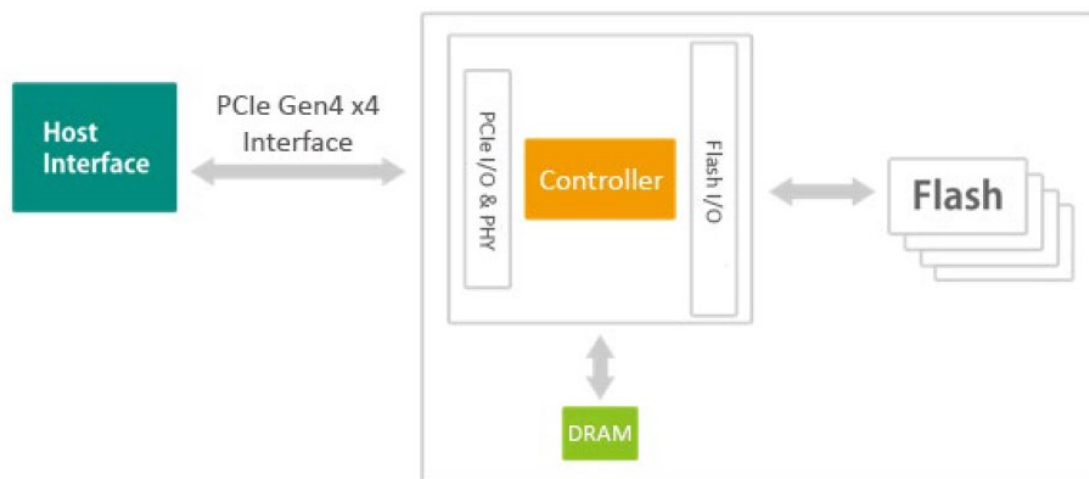
Note: The actual number of NAND flash used on Apacer PT160-M280 varies from capacities. The illustration is for reference only.

Figure 2-1 Functional Block Diagram

3. Pin Assignments

This connector does not support hot plug capability. There are a total of 75 pins. 12 pin locations are used for mechanical key locations; this allows such a module to plug into Key M connectors.
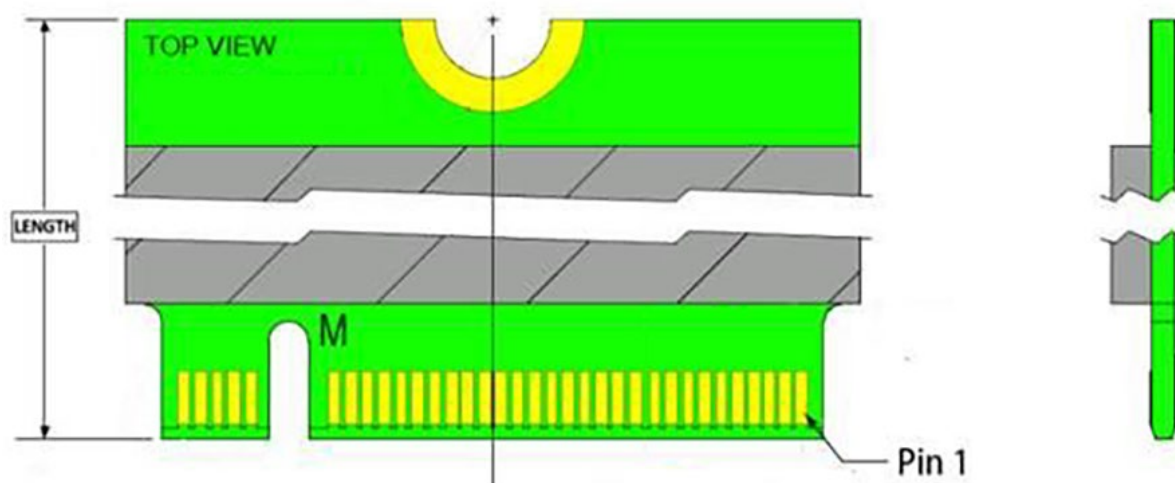
Figure 3-1 Pin Connectors

Table 3-1 Pin Assignments

Pin No.	Type	Description
1	GND	Ground
2	3.3 V	3.3V source
3	GND	Ground
4	3.3 V	3.3V source
5	PETn3	PCIe TX Differential signal defined by the PCI Express M.2 spec
6	PWRDIS (I)(0/1.8/3.3V)	No connect
7	PETp3	PCIe TX Differential signal defined by the PCI Express M.2 spec
8	PLN# (I)(0/1.8/3.3V)	No connect
9	GND	Ground
10	LED1#	Open drain, active low signal. These signals are used to allow the add-in card to provide status indicators via LED devices that will be provided by the system.
11	PERn3	PCIe RX Differential signal defined by the PCI Express M.2 spec
12	3.3 V	3.3V source
13	PERp3	PCIe RX Differential signals defined by the PCI Express M.2 spec
14	3.3 V	3.3V source
15	GND	Ground
16	3.3 V	3.3V source
17	PETn2	PCIe TX Differential signal defined by the PCI Express M.2 spec
18	3.3 V	3.3V source
19	PETp2	PCIe TX Differential signal defined by the PCI Express M.2 spec

Table 3-1 Pin Assignments

Pin No.	Type	Description
20	NC	No connect
21	GND	Ground
22	VIO 1.8 V	No connect
23	PERn2	PCIe RX Differential signal defined by the PCI Express M.2 spec
24	NC	No connect
25	PERp2	PCIe RX Differential signal defined by the PCI Express M.2 spec
26	NC	No connect
27	GND	Ground
28	NC	No connect
29	PETn1	PCIe TX Differential signal defined by the PCI Express M.2 spec
30	PLA_S3# (O)(0/1.8/3.3V)	No connect
31	PETp1	PCIe TX Differential signal defined by the PCI Express M.2 spec
32	GND	Ground
33	GND	Ground
34	USB_D+	No connect
35	PERn1	PCIe RX Differential signal defined by the PCI Express M.2 spec
36	USB_D-	No connect
37	PERp1	PCIe RX Differential signal defined by the PCI Express M.2 spec
38	GND	Ground
39	GND	Ground
40	SMB_CLK (I/O)(0/1.8V)	No connect
41	PETn0	PCIe TX Differential signal defined by the PCI Express M.2 spec
42	SMB_DATA (I/O)(0/1.8V)	No connect
43	PETp0	PCIe TX Differential signal defined by the PCI Express M.2 spec
44	ALERT# (O)(0/1.8V)	No connect
45	GND	Ground
46	NC	No connect
47	PERn0	PCIe RX Differential signal defined by the PCI Express M.2 spec
48	NC	No connect
49	PERp0	PCIe RX Differential signal defined by the PCI Express M.2 spec
50	PERST# (I)(0/1.8V/3.3V)	PE-Reset is a functional reset to the card as specification. defined by the PCIe Mini CEM
51	GND	Ground
52	CLKREQ# (I/O)(0/1.8V/3.3V)	Clock Request is a reference clock request signal as defined by the PCIe Mini CEM specification; Also used by L1 PM Substates.
53	REFCLKn	PCIe Reference Clock signals (100 MHz) spec. defined by the PCI Express M.2
54	PEWAKE# (I/O)(0/1.8V/3.3V)	No connect
55	REFCLKp	PCIe Reference Clock signals (100 MHz) spec. defined by the PCI Express M.2
56	Reserved for MFG_DATA	Reserved for Apacer use only[1]
57	GND	Ground
58	Reserved for MFG_CLOCK	Reserved for Apacer use only[1]

Table 3-1 Pin Assignments

Pin No.	Type	Description
59	Module Key M	Module Key
60	Module Key M	Module Key
61	Module Key M	Module Key
62	Module Key M	Module Key
63	Module Key M	Module Key
64	Module Key M	Module Key
65	Module Key M	Module Key
66	Module Key M	Module Key
67	NC	Reserved for Apacer use only[1]
68	SUSCLK (I)(0/1.8V/3.3V)	No connect
69	PEDET	No connect
70	3.3 V	3.3V source
71	GND	Ground
72	3.3 V	3.3V source
73	VIO_CFG (O)	Ground
74	3.3 V	3.3V source
75	GND	Ground

Note:
1.   Reserved by Apacer, please do not connect to a host.

4. Product Specifications

4.1 Capacity

Capacity specifications of PT160-M280 are available as shown in Table 4-1.

Table 4-1 Capacity Specifications

Capacity	Total bytes	Total LBA
4 TB	3,840,755,982,336	7,501,476,528
8 TB	7,681,501,126,656	15,002,931,888

Notes:
- Display of total bytes varies from operating systems.
- 1 GB = 1,000,000,000 bytes; 1 sector = 512 bytes.
- LBA count addressed in the table above indicates total user storage capacity and will remain the same throughout the lifespan of the device. However, the total usable capacity of the SSD is most likely to be less than the total physical capacity because a small portion of the capacity is reserved for device maintenance usages.

4.2 Performance

Performance of PT160-M280 is listed below in Table 4-2.

Table 4-2 Performance Specifications

Capacity / Performance	4 TB		8 TB
	Standard Temperature	Wide Temperature	
Sequential Read (MB/s)	6,920	6,820	6,970
Sequential Write (MB/s)	2,310	2,305	2,065
4K Random Read (IOPS)	909,000	554,000	899,000
4K Random Write (IOPS)	517,000	516,000	472,000

Notes:
- Results may differ from various flash configurations or host system setting.
- Sequential read/write is based on CrystalDiskMark 8.0.4 with file size 1,000MB.
- Random read/write is measured using IOMeter with Queue Depth 128.

4.3 Environmental Specifications

Environmental specifications of PT160-M280 are shown in Table 4-3.

Table 4-3 Environmental Specifications

Parameter	Type	Specifications
Temperature	Operating (Tc)	0°C to 70°C (Standard); -40°C to 85°C (Wide)
	Non-operating (Ta)	-55°C to 100°C
Vibration	Operating	7.69 GRMS, 20~2000 Hz/random (compliant with MIL-STD-810G)
	Non-operating	4.02 GRMS, 15~2000 Hz/random (compliant with MIL-STD-810G)
Shock	Operating	Acceleration, 50(G)/11(ms)/half sine (compliant with MIL-STD-202G)
	Non-operating	Acceleration, 1500(G)/0.5(ms)/half sine (compliant with MIL-STD-883K)

Notes:
- This Environmental Specification table indicates the conditions for testing the device. Real world usages may affect the results.
- Tc: case temperature; Ta: ambient temperature. The operating temperature is determined by the case temperature. Adequate airflow is advisable as it enables the device to maintain optimal temperatures, especially in environments with heavy workloads.

4.4 Mean Time Between Failures (MTBF)

Mean Time Between Failures (MTBF) is predicted based on reliability data for the individual components in PT160-M280. The prediction result for PT160-M280 is more than 3,000,000 hours.

Note: The MTBF is predicated and calculated based on "Telcordia Technologies Special Report, SR-332, Issue 3" method.

4.5 Certification and Compliance

PT160-M280 complies with the following standards:
- CE
- UKCA
- FCC
- RoHS
- MIL-STD-810G

4.6 Endurance

The endurance of a storage device is predicted by Drive Writes Per Day based on several factors related to usage, such as the amount of data written into the drive, block management conditions, and daily workload for the drive. Thus, key factors, such as Write Amplifications and the number of P/E cycles, can influence the lifespan of the drive.

Table 4-4 Endurance Specifications

Capacity	Drive Writes Per Day
4 TB	2.30
8 TB	1.54

Notes:
- This estimation complies with JEDEC random client workload.
- Flash vendor guaranteed 3D NAND TLC P/E cycle: 3K
- WAF may vary from capacity, flash configurations and writing behavior on each platform.
- 1 Terabyte = 1,024GB
- DWPD (Drive Writes Per Day) is calculated based on the number of times that user overwrites the entire capacity of an SSD per day of its lifetime during the warranty period. (3D NAND TLC warranty: 3 years)

4.7 LED Indicator Behavior

The behavior of the PT160-M280 LED indicators is described in Table 4-5.

Table 4-5 LED Behavior

Location	LED	Description
LED A	Power	LED glows solidly when power is on
LED B	DAS	LED blinks when the drive is being accessed

5. Flash Management

5.1 Error Correction/Detection

PT160-M280 implements a hardware ECC scheme, based on the Low Density Parity Check (LDPC). LDPC is a class of linear block error correcting code which has apparent coding gain over BCH code because LDPC code includes both hard decoding and soft decoding algorithms. With the error rate decreasing, LDPC can extend SSD endurance and increase data reliability while reading raw data inside a flash chip.

5.2 Bad Block Management

Current production technology is unable to guarantee total reliability of NAND flash memory array. When a flash memory device leaves factory, it comes with a minimal number of initial bad blocks during production or out-of-factory as there is no currently known technology that produce flash chips free of bad blocks. In addition, bad blocks may develop during program/erase cycles. Since bad blocks are inevitable, the solution is to keep them in control. Apacer flash devices are programmed with ECC, page mapping technique and S.M.A.R.T to reduce invalidity or error. Once bad blocks are detected, data in those blocks will be transferred to free blocks and error will be corrected by designated algorithms.

5.3 Global Wear Leveling

Flash memory devices differ from Hard Disk Drives (HDDs) in terms of how blocks are utilized. For HDDs, when a change is made to stored data, like erase or update, the controller mechanism on HDDs will perform overwrites on blocks. Unlike HDDs, flash blocks cannot be overwritten and each P/E cycle wears down the lifespan of blocks gradually. Repeatedly program/erase cycles performed on the same memory cells will eventually cause some blocks to age faster than others. This would bring flash storages to their end of service term sooner. Global wear leveling is an important mechanism that levels out the wearing of all blocks so that the wearing-down of all blocks can be almost evenly distributed. This will increase the lifespan of SSDs.

5.4 Power Failure Management

Power Failure Management plays a crucial role when power supply becomes unstable. Power disruption may occur when users are storing data into the SSD, leading to instability in the drive. However, with Power Failure Management, a firmware protection mechanism will be activated to scan pages and blocks once power is resumed. Valid data will be transferred to new blocks for merging and the mapping table will be rebuilt. Therefore, data reliability can be reinforced, preventing damage to data stored in the NAND Flash.

Note: The controller unit of this product model is designed with a DRAM as a write cache for improved performance and data efficiency. Though unlikely to happen in most cases, the data cached in the volatile DRAM might be potentially affected if a sudden power loss takes place before the cached data is flushed into non-volatile NAND flash memory.

5.5 TRIM

TRIM is a feature which helps improve the read/write performance and speed of solid-state drives (SSD). Unlike hard disk drives (HDD), SSDs are not able to overwrite existing data, so the available space gradually becomes smaller with each use. With the TRIM command, the operating system can inform the SSD which blocks of data are no longer in use and can be removed permanently. Thus, the SSD will perform the erase action, which prevents unused data from occupying blocks all the time.

5.6 Flash Translation Layer – Page Mapping

Page mapping is an advanced flash management technology whose essence lies in the ability to gather data, distribute the data into flash pages automatically, and then schedule the data to be evenly written. Page-level mapping uses one page as the unit of mapping. The most important characteristic is that each logical page can be mapped to any physical page on the flash memory device. This mapping algorithm allows different sizes of data to be written to a block as if the data is written to a data pool and it does not need to take extra operations to process a write command. Thus, page mapping is adopted to increase random access speed and improve SSD lifespan, reduce block erase frequency, and achieve optimized performance and lifespan.

5.7 SMART Read Refresh™

Apacer's SMART Read Refresh plays a proactive role in avoiding read disturb errors from occurring to ensure health status of all blocks of NAND flash. Developed for read-intensive applications in particular, SMART Read Refresh is employed to make sure that during read operations, when the read operation threshold is reached, the data is refreshed by re-writing it to a different block for subsequent use.

5.8 NVMe Secure Erase

NVMe Secure Erase is an NVMe drive sanitize command currently embedded in most of the storage drives. Defined in NVMe specifications, NVMe Secure Erase is part of Format NVM command that allows storage drives to erase all user data areas. The erase process usually runs on the firmware level as most of the NVMe-based storage media currently in the market are built-in with this command. NVMe Secure Erase can securely wipe out the user data in the drive and protects it from malicious attack.

6. Security and Reliability Features

6.1 Advanced Encryption Standard

Advanced Encryption Standard (AES) is a specification for the encryption of electronic data. AES has been adopted by the U.S. government since 2001 to protect classified information and is now widely implemented in embedded computing applications. The AES algorithm used in software and hardware is symmetric so that encrypting/decrypting requires the same encryption key. Without the key, the encrypted data is inaccessible to ensure information security.

Notably in flash memory applications, AES 256-bit hardware encryption is the mainstream to protect sensitive or confidential data. The hardware encryption provides better performance, reliability, and security than software encryption. It uses a dedicated processor, which is built inside the controller, to process the encryption and decryption. This enormously shortens the processing time and makes it efficient.

6.2 Thermal Sensor

Apacer Thermal Sensor is a digital temperature sensor with serial interface. By using designated pins for transmission, storage device owners are able to read temperature data.

6.3 Thermal Throttling

Thermal throttling can monitor the temperature of the SSD equipped with a built-in thermal sensor via S.M.A.R.T. commands. This method can ensure the temperature of the device stays within temperature limits by drive throttling, i.e. reducing the speed of the drive when the device temperature reaches the threshold level, so as to prevent overheating, guarantee data reliability, and prolong product lifespan. When the temperature exceeds the maximum threshold level, thermal throttling will be triggered to reduce performance step by step to prevent hardware components from being damaged. Performance is only permitted to drop to the extent necessary for recovering a stable temperature to cool down the device's temperature. Once the temperature decreases to the minimum threshold value, transfer speeds will rise back to its optimum performance level.

6.4 Sidefill

Apacer's Sidefill technology strengthens the connections between solder joints and their board, making them more robust and vibration-resistant. It also allows for heat dissipation to offset thermal damage.

6.5 End-to-End Data Protection

End-to-End Data Protection is a feature implemented in Apacer SSD products that extends error control to cover the entire path from the host computer to the drive and back, and ensure data integrity at multiple points in the path to enable reliable delivery of data transfers. Unlike ECC which does not exhibit the ability to determine the occurrence of errors throughout the process of data transmission, End-to-End Data Protection allows SSD controller to identify an error created anywhere in the path and report the error to the host computer before it is written to the drive. This error-checking and error-reporting mechanism therefore guarantees the trustworthiness and reliability of the SSD.

6.6 Heat Spreader

In many applications, SSDs are subject to challenging conditions. If the working environment is already hot, and the SSD's operation causes it to increase in temperature as well, the result could be damage to the hardware or corrupted data. For this reason, Apacer's graphene heat spreader is developed for heat dissipation to cool both the NAND Flash and the Controller IC, while still allowing an SSD to deliver high-speed performance, as well as prevent heat-related damage from occurring.

7. Software Interface

7.1 Command Set

Table 7-1 summarizes the commands supported by PT160-M280.

Table 7-1 Admin Commands

Opcode	Command Description
00h	Delete I/O Submission Queue
01h	Create I/O Submission Queue
02h	Get Log Page
04h	Delete I/O Completion Queue
05h	Create I/O Completion Queue
06h	Identify
08h	Abort
09h	Set Features
0Ah	Get Features
0Ch	Asynchronous Event Request
10h	Firmware Commit
11h	Firmware Image Download
14h	Device Self-test

Table 7-2 Admin Commands – NVM Command Set Specific

Opcode	Command Description
80h	Format NVM
81h	Security Send
82h	Security Receive

Table 7-3 NVM Commands

Opcode	Command Description
00h	Flush
01h	Write
02h	Read
05h	Compare
08h	Write Zeroes
09h	Dataset Management

7.2 S.M.A.R.T.

SMART, an acronym for Self-Monitoring, Analysis and Reporting Technology, is an open standard that allows a hard disk drive to automatically detect its health and report potential failures. When a failure is recorded by SMART, users can choose to replace the drive to prevent unexpected outage or data loss. Moreover, SMART can inform users of impending failures while there is still time to perform proactive actions, such as copy data to another device.

Table 7-4 SMART (02h)

Byte	Length	Description
0	1	Critical Warning
1-2	2	Composite Temperature
3	1	Available Spare
4	1	Available Spare Threshold
5	1	Percentage Used (Average Erase Count / P/E Cycle Count)
6-31	26	Reserved
32-47	16	Data Units Read
48-63	16	Data Units Written
64-79	16	Host Read Commands
80-95	16	Host Write Commands
96-111	16	Controller Busy Time
112-127	16	Power Cycles
128-143	16	Power On Hours
144-159	16	Unsafe Shutdowns
160-175	16	Media and Data Integrity Errors
176-191	16	Number of Error Information Log Entries
192-195	4	Warning Composite Temperature Time
196-199	4	Critical Composite Temperature Time
200-201	2	Temperature Sensor 1: Controller Temperature
202-203	2	Temperature Sensor 2: PCB Temperature
204-205	2	Temperature Sensor 3: NAND Flash Temperature
206-207	2	Temperature Sensor 4
208-209	2	Temperature Sensor 5
210-211	2	Temperature Sensor 6
212-213	2	Temperature Sensor 7
214-215	2	Temperature Sensor 8
216-511	296	Reserved

Note: Temperature display of the Temperature Sensor from 1 to 8 (corresponding bytes from 200 to 215) is not supported if the return value is 0h.

Table 7-5 SMART (C0h)

Byte	Length	Description
0-255	256	Reserved
256-257	2	SSD Protect Mode
258-261	4	Host Read UNC Count
262-265	4	Reserved
266-269	4	CRC Error Count
270-273	4	Total Early Bad Block Count
274-277	4	Total Later Bad Block Count
278-281	4	Max Erase Count
282-285	4	Average Erase Count
286-289	4	Program Fail Count
290-293	4	Erase Fail Count
294-301	8	Flash Write Sector
302-305	4	Total Spare Block
306-309	4	Current Spare Block
310-313	4	Read Retry Count
314-511	210	Reserved

8. Electrical Specifications

8.1 Operating Voltage

Table 8-1 lists the supply voltage for PT160-M280.

Table 8-1 Operating Range

Item	Range
Supply Voltage	3.3V ± 5%

8.2 Power Consumption

Table 8-2 lists the power consumption for PT160-M280.

Table 8-2 Power Consumption

| Capacity / Mode	Unit	4 TB		8 TB
		Standard Temperature	Wide Temperature	
Active (Max.)	mA	3,310	2,930	3,750
Idle		815	810	900

Notes:
- All values are typical and may vary depending on flash configurations or host system settings.
- Power consumption is measured using CrystalDiskMark 8.0.4 with file size 1,000MB.
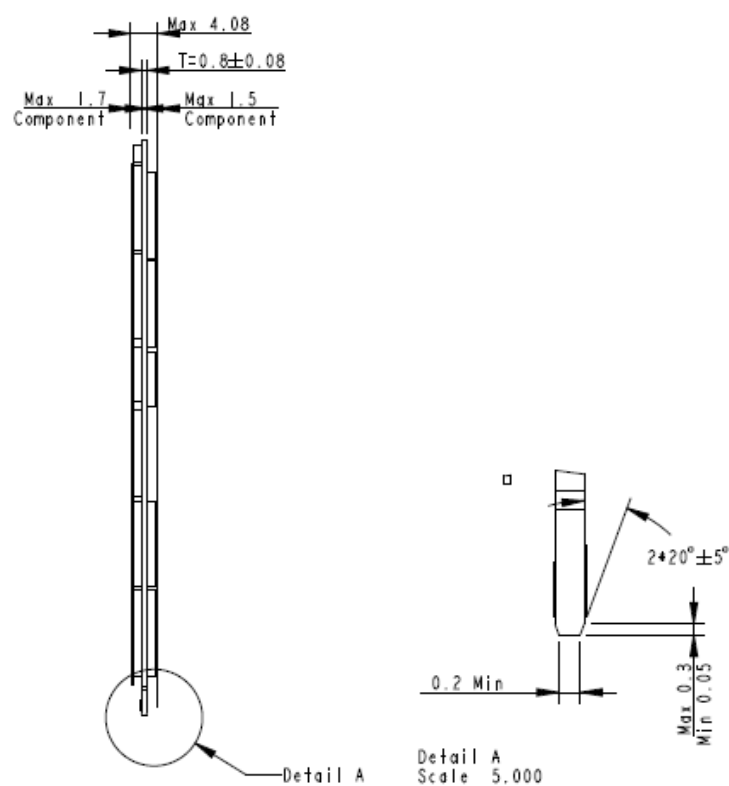
9. Mechanical Specifications

Table 9-1 Physical Information

Parameter	Unit	4 TB	8 TB
Length	mm	80.00 ± 0.15	
Width		22.00 ± 0.15	
Height (Max.)		4.08	
Weight	g ± 5%	11.9	11.9

Top View
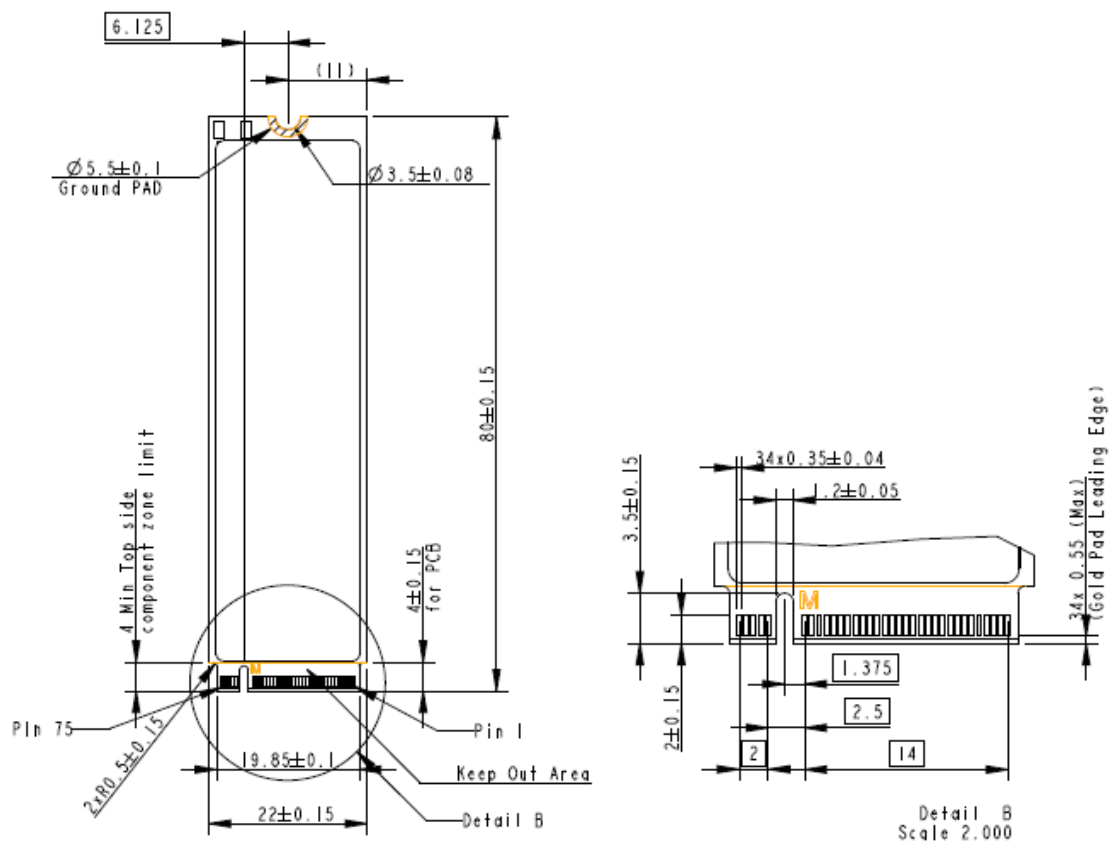
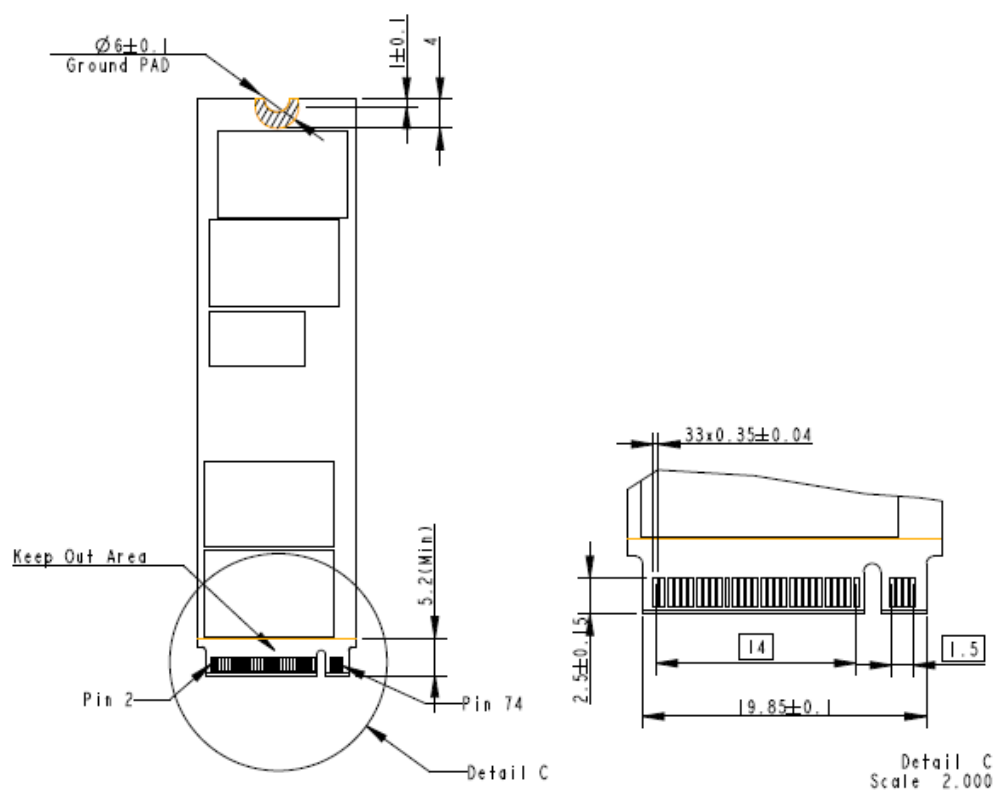**Side View**

Bottom View

Figure 9-1 Physical Dimensions

10. Product Ordering Information

10.1 Product Code Designations

Apacer's PT160-M280 SSD is available in different configurations and densities. See the chart below for a comprehensive list of options for the PT160-M280 series devices.

Code	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16
	B	9	2	.	1	6	C	X	X	U	.	0	0	1	0	1

Code 1-3 **(Product Line & Form Factor)**	PCIe M.2 2280
Code 5-6 **(Model/Solution)**	PT160-M280
Code 7-8 **(Product Capacity)**	CN: 4TB CP: 8TB
Code 9 **(Flash Type & Product Temp)**	G: 3D TLC Standard Temperature H: 3D TLC Wide Temperature
Code 10 **(Product Spec)**	Double-sided M key with heat spreader
Code 12-14 **(Version Number)**	Random numbers generated by system
Code 15-16 **(Firmware Version)**	Thermal Sensor

10.2 Valid Combinations

The following table lists the available models of the PT160-M280 series which are in mass production or will be in mass production. Consult your Apacer sales representative to confirm availability of valid combinations and to determine availability of new combinations.

Capacity	Standard Temperature	Wide Temperature
4TB	B92.16CNGU.00101	B92.16CNHU.00101
8TB	B92.16CPGU.00101	N/A

Revision History

Revision	Description	Date
0.1	Preliminary release	8/9/2023
0.2	- Added 8TB support - Removed Heatsink and added Heat Spreader support - Updated Performance, Temperature Range, Power Consumption, Dimensions and Net weight on Specifications Overview page and Table 4-2, 4-3, 8-2, and 9-1 - Added 10. Product Ordering Information	1/23/2024
1.0	- Added Power Management to Specifications Overview - Updated Performance, Endurance, storage temperature, and Power Consumption on Specifications Overview page and Table 4-2, 4-3, 4-4, and 8-2 - Updated 7.1 Command Set	1/31/2024
1.1	Added a note regarding temperature at Table 4-3	4/12/2024
1.2	Added 4.7 LED Indicator Behavior	7/4/2024

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